Search Notes	
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Application/Control No. 10/749,670 Examiner	Applicant(s)/Patent under Reexamination		
	10/749,670	KIM ET AL.	
	Examiner	Art Unit	_
	Dennis Posario	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
782	144-150	5/17107 10/5/07	DR DR		
	141	12/18/07	DIS		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
(Codated)	DATE	EXMR	
(Fast, all dB)	5/17107	DR	
	(6/4/07)		
	[12/13/07)(DR)	
IEEE-inspection (near) water and	5/17/07	PR	
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TEEF- threshold	1015/07	V R	
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CHEAT image	12/13/07	DR	
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